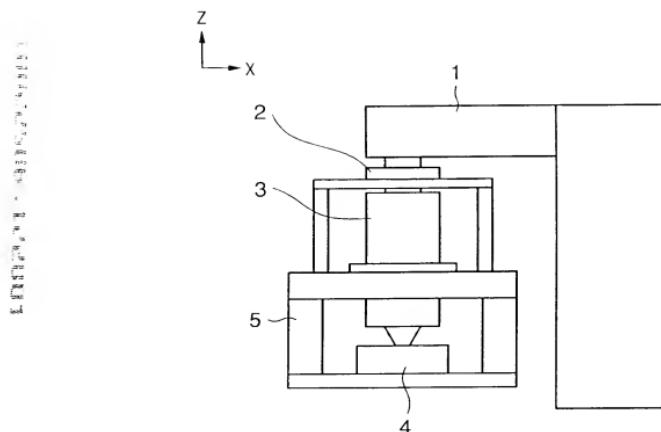


FIG. 1



F I G. 2

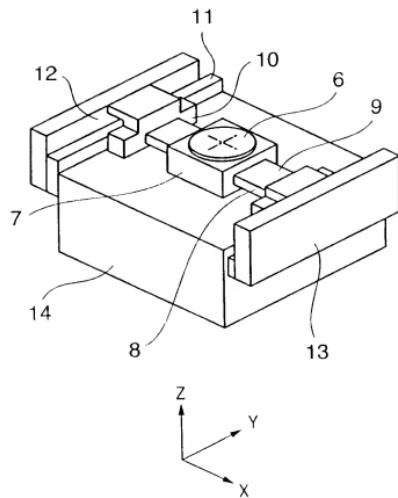


FIG. 3A

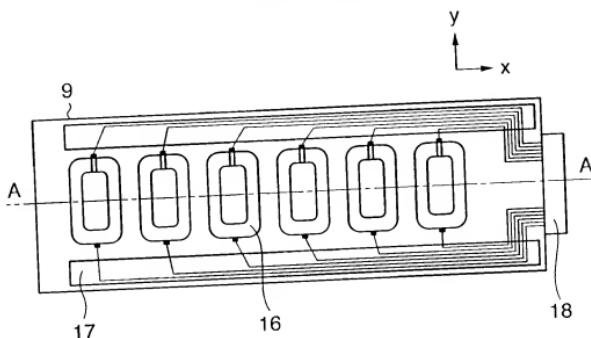


FIG. 3B

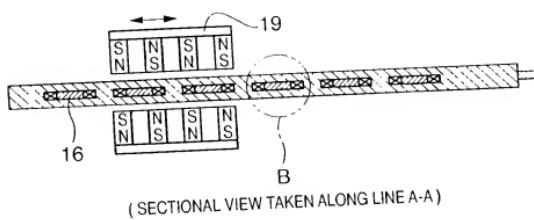
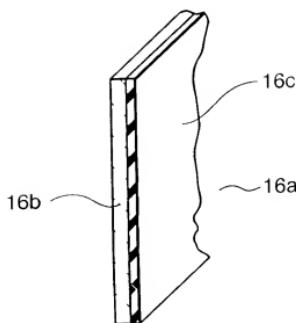


FIG. 4



F I G. 5

ENLARGED VIEW OF PORTION B

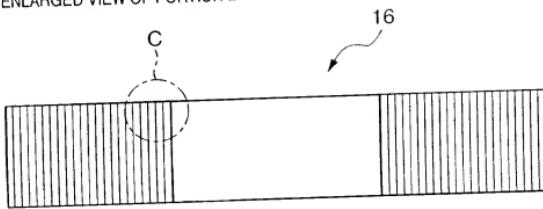


FIG. 6

ENLARGED VIEW OF PORTION C

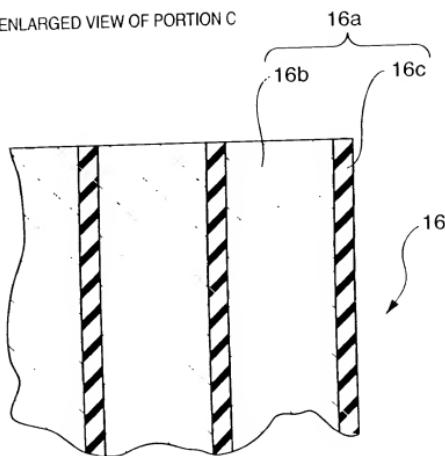


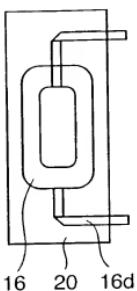
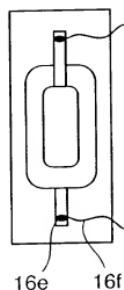
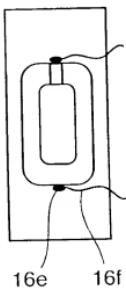
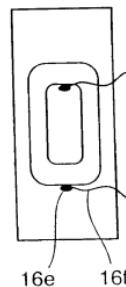
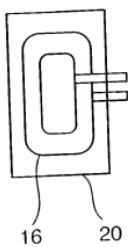
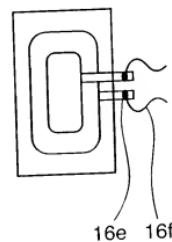
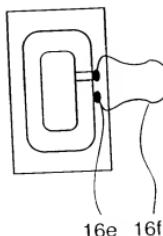
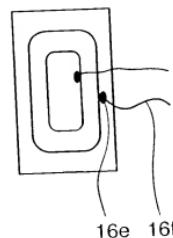
FIG. 7A**FIG. 7B****FIG. 7C****FIG. 7D**

FIG. 8A**FIG. 8B****FIG. 8C****FIG. 8D**

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FIG. 9A

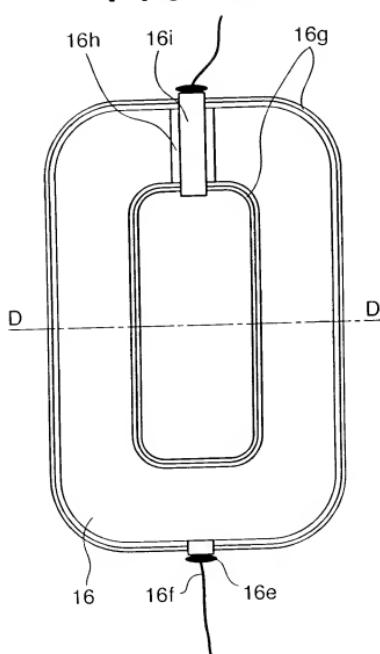


FIG. 9B

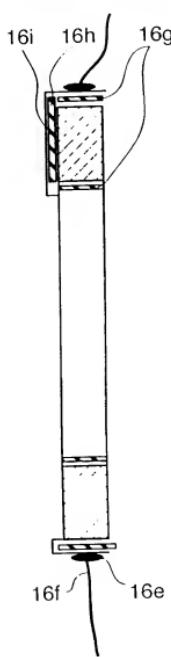
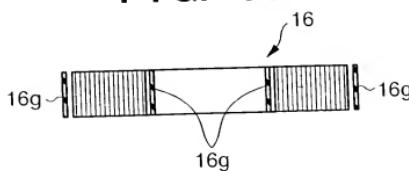
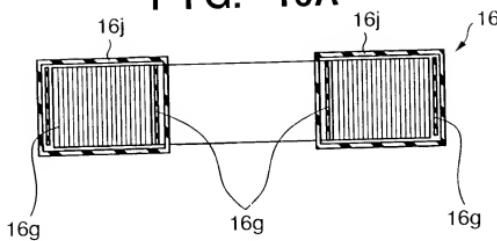


FIG. 9C

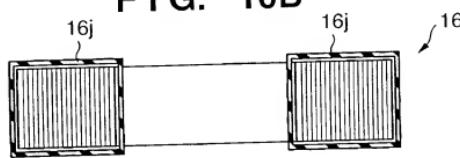


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F I G. 10A



F I G. 10B



F I G. 10C

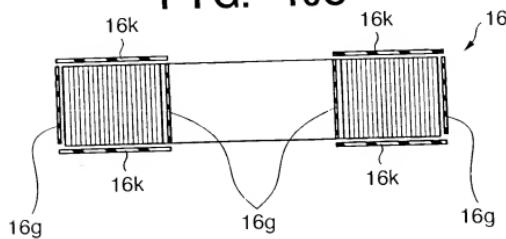


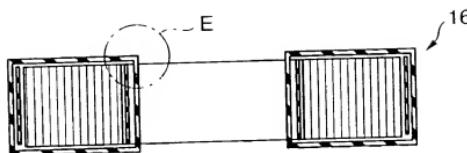
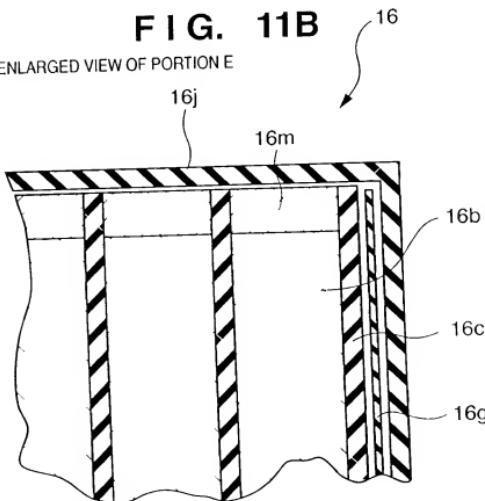
FIG. 11A**FIG. 11B**
ENLARGED VIEW OF PORTION E

FIG. 12A

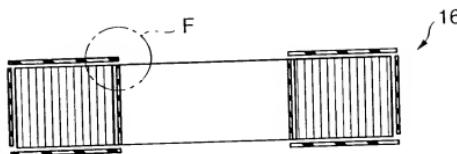
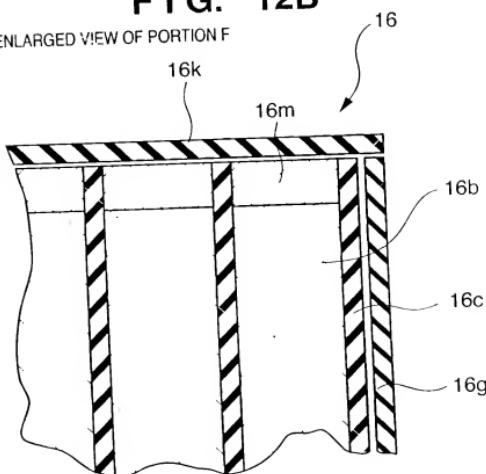


FIG. 12B
ENLARGED VIEW OF PORTION F



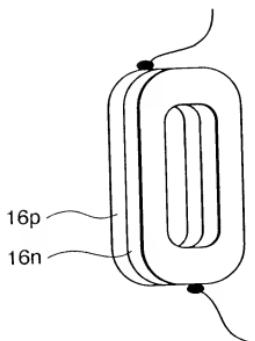
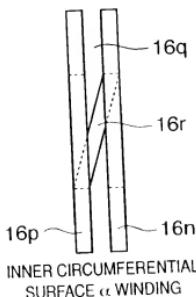
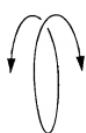
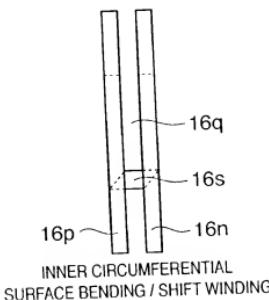
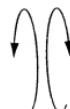
F I G. 13A**F I G. 13B****F I G. 13C**

FIG. 14

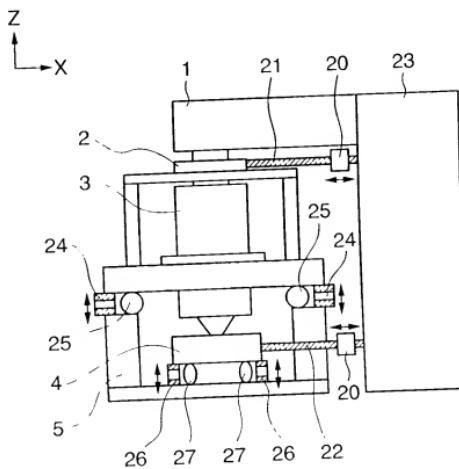


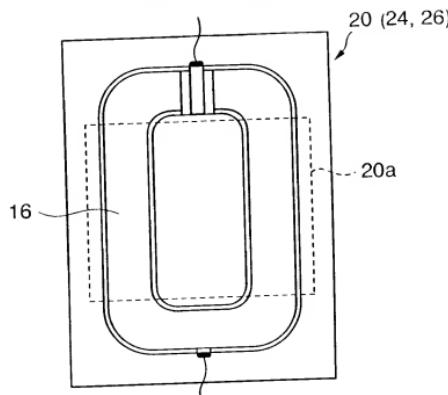
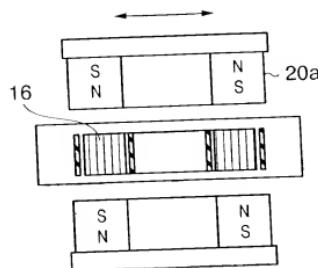
FIG. 15A**FIG. 15B**

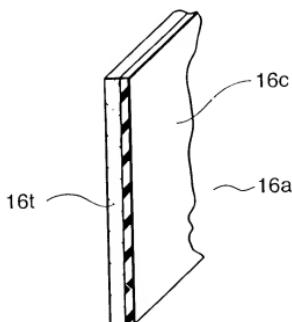
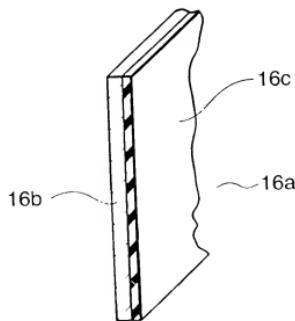
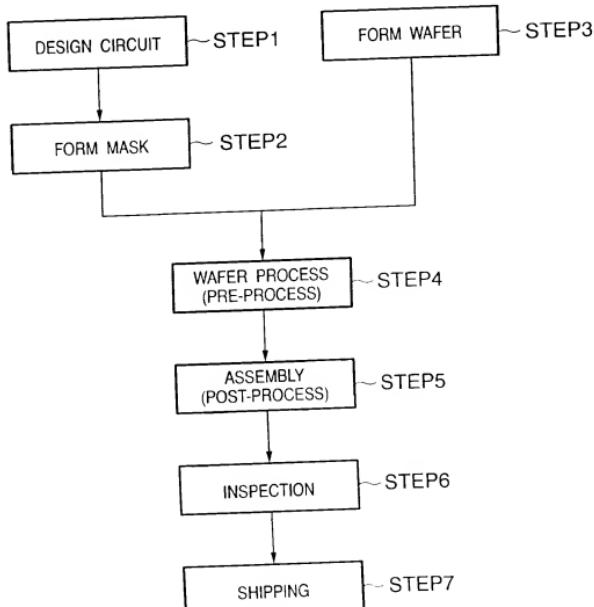
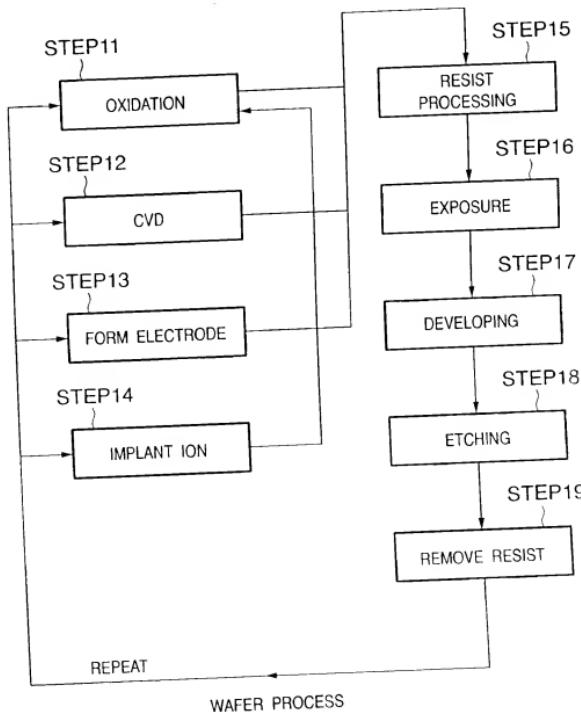
FIG. 16A**FIG. 16B**

FIG. 17



SEMICONDUCTOR DEVICE MANUFACTURING FLOW

FIG. 18



T E C H N I C A L D O C U M E N T

FIG. 19A

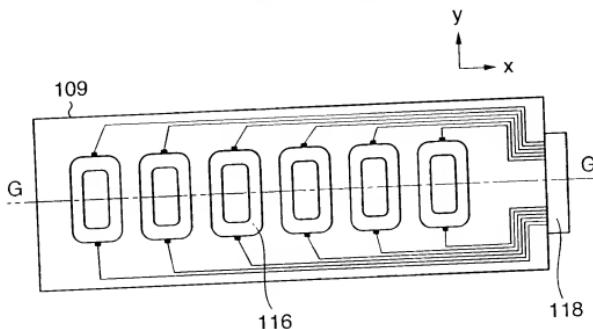
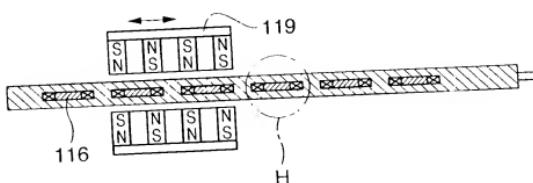


FIG. 19B



(SECTIONAL VIEW TAKEN ALONG LINE G-G)

FIG. 20

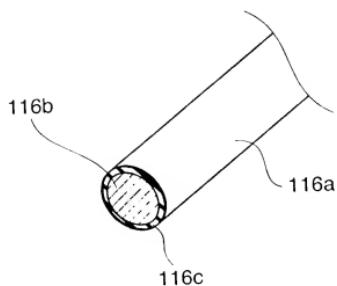


FIG. 21

ENLARGED VIEW OF PORTION H

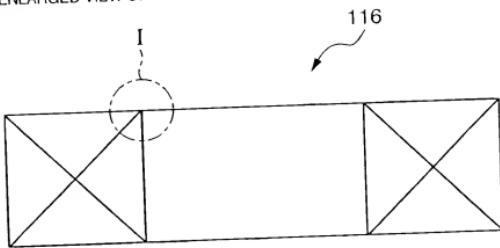


FIG. 22

ENLARGED VIEW OF PORTION I

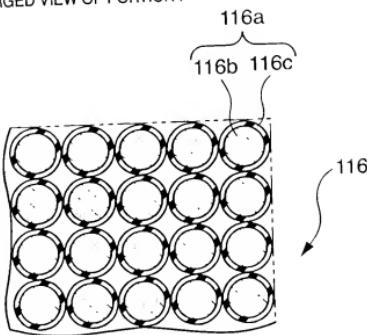


FIG. 23A

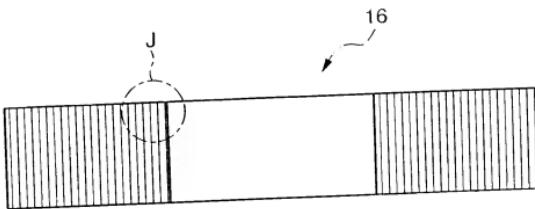
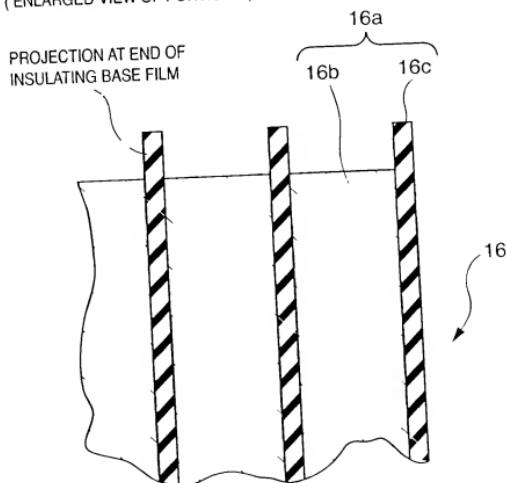


FIG. 23B

(ENLARGED VIEW OF PORTION J)



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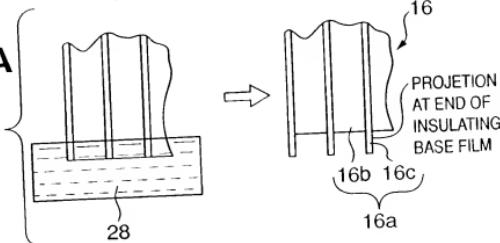
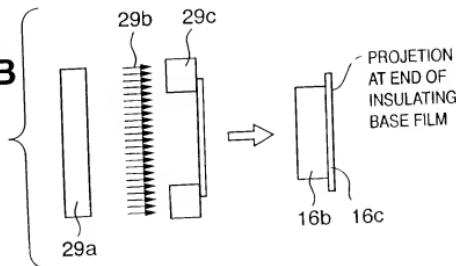
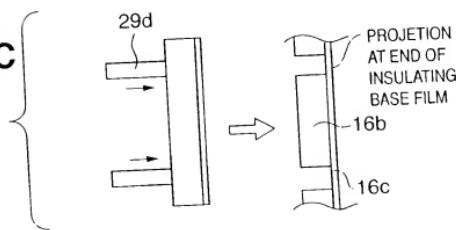
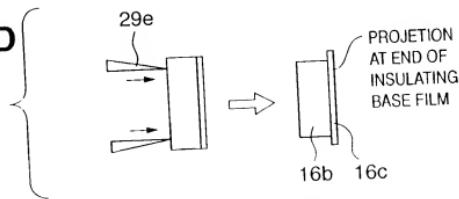
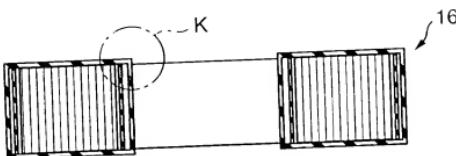
FIG. 24A**FIG. 24B****FIG. 24C****FIG. 24D**

FIG. 25A**FIG. 25B**

(ENLARGED VIEW OF PORTION K)

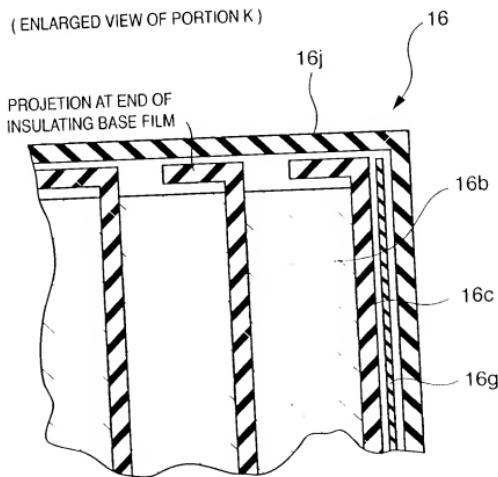


FIG. 26A

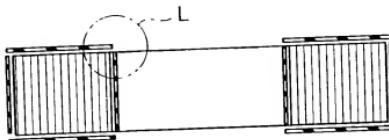
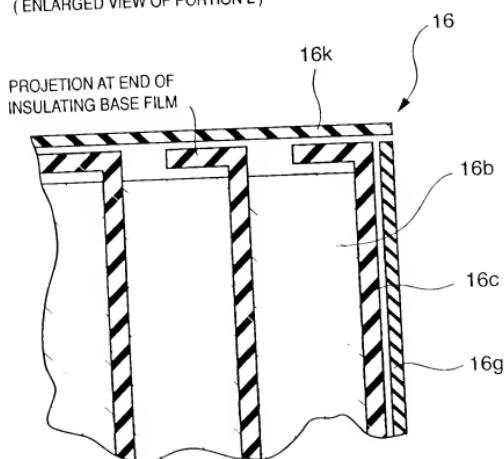


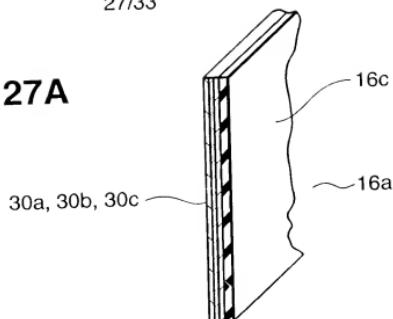
FIG. 26B

(ENLARGED VIEW OF PORTION L)

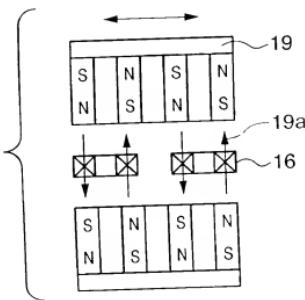


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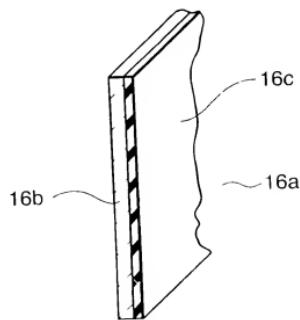
F I G. 27A



F I G. 27B

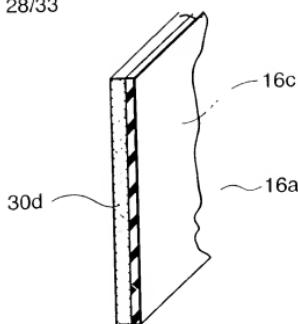


F I G. 27C

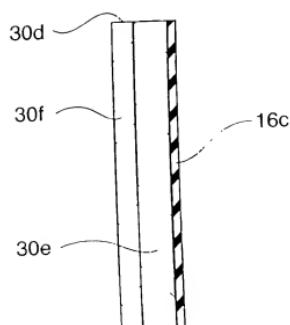


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F I G. 28A



F I G. 28B



F I G. 28C

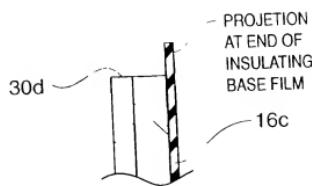
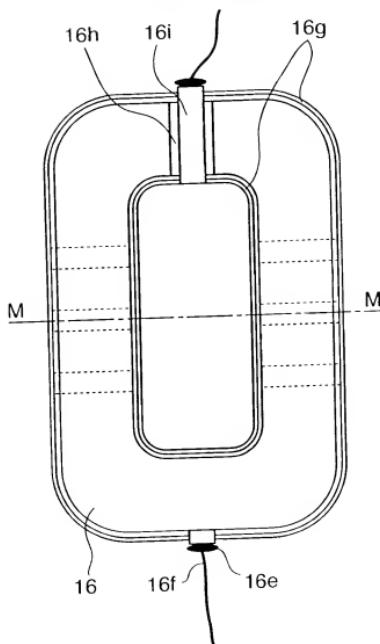
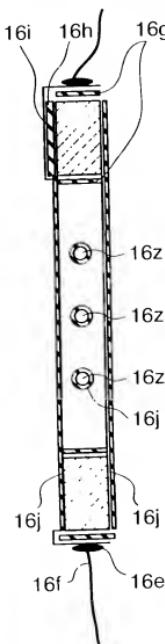
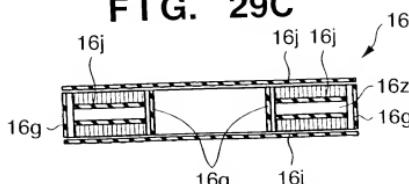


FIG. 29A**FIG. 29B****FIG. 29C**

(SECTIONAL VIEW TAKEN ALONG LINE M-M)

FIG. 30

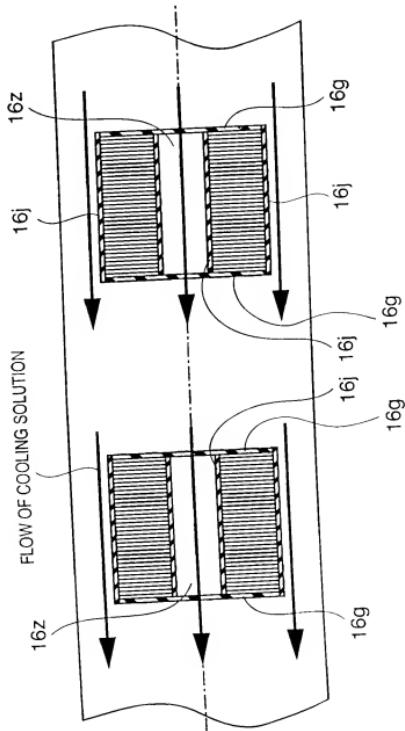


FIG. 31

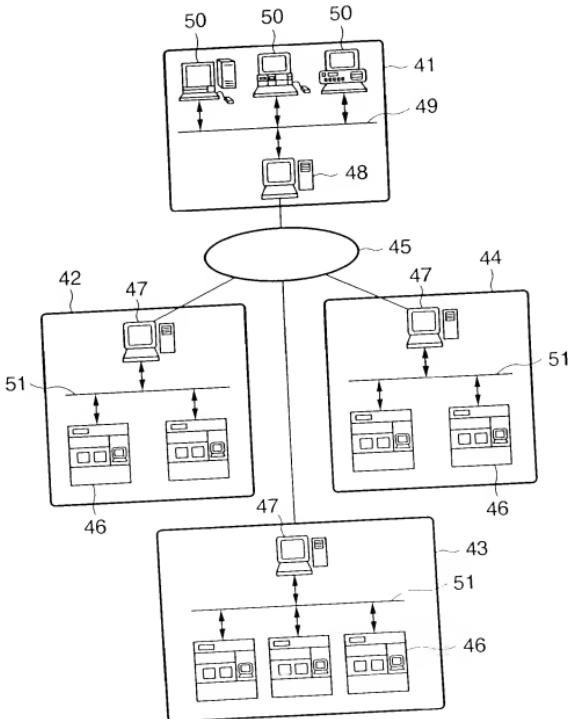


FIG. 32

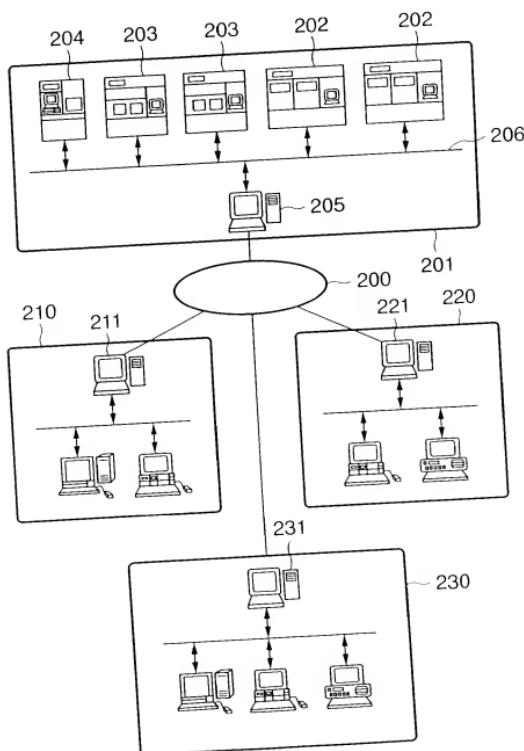


FIG. 33

URL <http://www.maintain.co.jp/db/input.html>

TROUBLE DB INPUT WINDOW

OCCURRENCE DATE [2000/3/15] ~ 404

TYPE OF APPARATUS [*****] ~ 401

OBJECT [OPERATION ERROR (START-UP ERROR)] ~ 403

DEVICE S/N [465NS4580001] ~ 402

DEGREE OF URGENCY [D] ~ 405

SYMPTOM [LED KEEPS FLICKERING AFTER POWER ON] ~ 406

REMEDY [POWER ON AGAIN (PRESS RED BUTTON IN ACTIVATION)] ~ 407

PROGRESS [INTERIM HAS BEEN DONE] ~ 408

[SEND] 410 [RESET] 411 ~ 412

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